

- =====
- Threshold voltage in CMOS Defined as : The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the source of the MOS transistor below which the drain to source current, I_{DS} effectively drops to zero.

Threshold voltage in CMOS Defined as : The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the source of the MOS transistor below which the drain to source current, I_{DS} effectively drops to zero.

- ☒ True
☐ False

- =====
- Fringe Capacitance for wire becomes less important as process goes low

Fringe Capacitance for wire becomes less important as process goes low

- ☐ True
☒ False

- =====
- The minimum width and minimum spacing provided by:

The minimum width and minimum spacing provided by:

- ☒ A. process file
☐ B. Layout Engineer
☐ C. only by design owner
☐ D. Logic designer

- =====
- What are the operation regions for a MOS transistor?

What are the operation regions for a MOS transistor?

- ☒ A. Cutoff region
- ☒ B. Linear region
- ☐ C. None
- ☒ D. Saturation Region
- ☐ E. MOS device has only one region only

- =====
- Choose the option below that is regarded as a step in the process of preparing various Silicon wafers process

Choose the option below that is regarded as a step in the process of preparing various Silicon wafers process

- ☒ A. Etching and Wafer cleaning.
- ☐ B. Verilog code preparation
- ☒ C. Crystal growth & doping
- ☒ D. Wafer polishing

=====

Some of advantages of IC are :

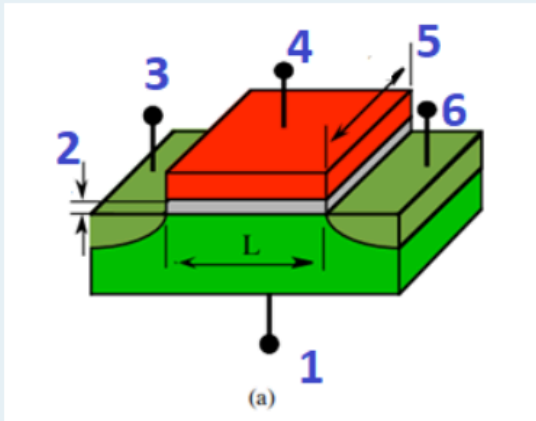
Some of advantages of IC are :

- ☐ A. Design Complexity is large
- ☐ B. Cost is High
- ☒ C. Size is less
- ☒ D. Less Power Dissipation
- ☒ E. High Speed

- Please correctly associate the number with the corresponding transistor part .

Please correctly associate the number with the corresponding transistor part .

|



Gate	<input type="text" value="4"/>
Width	<input type="text" value="5"/>
Drain	<input type="text" value="6"/>
Tox	<input type="text" value="2"/>
Source	<input type="text" value="3"/>

- ----- connects between 2 segments of metal layers

Question 1

Complete

Mark 1.00 out of 1.00

Flag question

----- connects between 2 segments of metal layers

- ☐ A. contact
- ☒ B. via
- ☐ C. poly
- ☐ D. diffusion

The correct answer is: via

- For constraints, the clock period has to be _____ than the data path delay

Question 7

Complete

Mark 1.00 out of 1.00

Flag question

For constraints, the clock period has to be _____ than the data path delay

- ☐ A. same
- ☐ B. NA
- ☐ C. shorter
- ☒ D. longer

The correct answer is: longer

- We always have to _____ our fast paths down so they arrive along with our slowest path

Question 6

Complete

Mark 1.00 out of 1.00

Flag question

We always have to _____ our fast paths down so they arrive along with our slowest path

- ☐ A. NA
- ☐ B. fasten
- ☒ C. slow
- ☐ D. keep the same

The correct answer is: slow

- Indicate whether each of the following has been increasing (↑) or decreasing (↓) with process scaling for synchronous integrated circuits.
- Dynamic power consumption as a proportion of total power consumption:

Question 3

Complete

Mark 0.75 out of 1.00

Remove flag

Indicate whether each of the following has been increasing (↑) or decreasing (↓) with process scaling for synchronous integrated circuits.

Dynamic power consumption as a proportion of total power consumption:

Power consumption per device per switching event:

(a) Clock frequency:

tox:

The correct answer is: Dynamic power consumption as a proportion of total power consumption: → ↓, Power consumption per device per switching event: → ↓, (a) Clock frequency: → ↑, tox: → ↓

- =====
- Which of these is considered a process for IC fabrication?

Which of these is considered a process for IC fabrication?

- ☒ A. Isolation technique
- ☒ B. Assembly processing & Packaging
- ☒ C. Silicon wafer Preparation
- ☒ D. Photolithography
- ☒ E. Ion Implantation
- ☐ F. Simulations
- ☒ G. Epitaxial Growth

- ☒ H. Metallization

- =====
- Temperature does not affect RC of the wire ?

Temperature does not affect RC of the wire ?

- ☐ True
- ☒ False

- =====
- If we could make all paths have equal delays, we wouldn't need sequential logic

Question **4**

Complete

Mark 0.00 out of 1.00

🚩 Flag question

If we could make all paths have equal delays, we wouldn't need sequential logic

- ☐ True
- ☒ False

The correct answer is 'True'.

- Determine Elmore delay between nodes s and d.

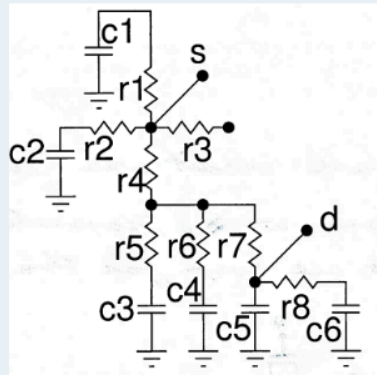
Question 2

Complete

Mark 1.00 out of 1.00

Flag question

Determine Elmore delay between nodes s and d.



d

- ☐ A. $T = (C3+C4+C5+C6)R4 + (C5+C6)(R4+R7)$
- ☐ B. $T = (C3+C4)R7 + (C5+C6)(R7)$
- ☐ C. $T = (C3+C4+C5+C6)(R4+R7)$
- ☒ D. $T = (C3+C4)R4 + (C5+C6)(R4+R7)$

$$\tau = C_3(r_4) + C_4(r_4) + C_5(r_4 + r_7) + C_6(r_4 + r_7)$$

$$\tau = (C_3 + C_4)r_4 + (C_5 + C_6)(r_4 + r_7)$$

- ----- The data path is so short that it passes through several registers during the same clock cycle.

Question 5

Complete

Mark 1.00 out of 1.00

Flag question

----- The data path is so short that it passes through several registers during the same clock cycle.

- ☐ A. buffer delay
- ☐ B. NA
- ☐ C. Max Delay
- ☒ D. Min Delay

The correct answer is: Min Delay

- what function this circuit represent

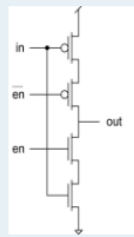
Question 4

Complete

Mark 1.00 out of 1.00

Flag question

what function this circuit represent



- ☒ A. tri-state buffer
- ☐ B. NA
- ☐ C. pass gate
- ☐ D. latch
- ☐ E. flip-flop

- _____ occur due to the logic changing before thold has passed.
This is not a function of cycle time – it is relative to a single clock edge

Question 5

Complete

Mark 1.00 out of 1.00

Flag question

_____ occur due to the logic changing before thold has passed. This is not a function of cycle time – it is relative to a single clock edge

- ☒ A. Hold problems
- ☐ B. NA
- ☐ C. Setup problems

The correct answer is: Hold problems

- ----- The data path is so short that it passes through several registers during the same clock cycle.

Question 7

Complete

Mark 1.00 out of 1.00

Flag question

----- The data path is so short that it passes through several registers during the same clock cycle.

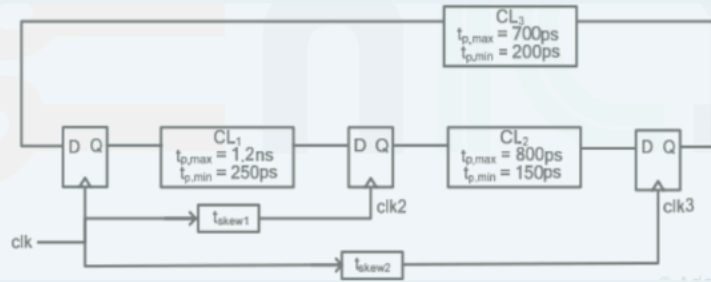
- ☐ A. Max Delay
- ☒ B. Min Delay
- ☐ C. buffer delay
- ☐ D. NA

The correct answer is: Min Delay

- We are given a synchronous network with:

Complete
Mark 5.00 out of 5.00
Flag question

$t_{CQ} = 150\text{ps}$, $t_{\text{setup}} = 50\text{ps}$, $t_{\text{hold}} = 100\text{ps}$, $t_{\text{jitter}} = 0$
 $t_{\text{skew1}} = -100\text{ps}$, $t_{\text{skew2}} = 50\text{ps}$



How many paths are there ?

What is the Max frequency can run at

- ☒ A. 3 paths
- ☒ B. 666MHz
- ☐ C. 1.05GHz
- ☐ D. 1.17GHz

• We'll find the setup constraints for each path:

Path 1: $T_1 + t_{\text{skew1}} > t_{\text{cq1}} + t_{\text{p,max}}(CL_1) + t_{\text{setup2}}$
 $T_1 > 150\text{p} + 1.2\text{n} + 50\text{p} + 100\text{p} = 1500\text{p} = 1.5\text{ns} \rightarrow 666\text{MHz}$

Path 2: $T_2 + (t_{\text{skew2}} - t_{\text{skew1}}) > t_{\text{cq2}} + t_{\text{p,max}}(CL_2) + t_{\text{setup3}}$
 $T_2 > 150\text{p} + 800\text{p} + 50\text{p} - 150\text{p} = 850\text{p} \rightarrow 1.17\text{GHz}$

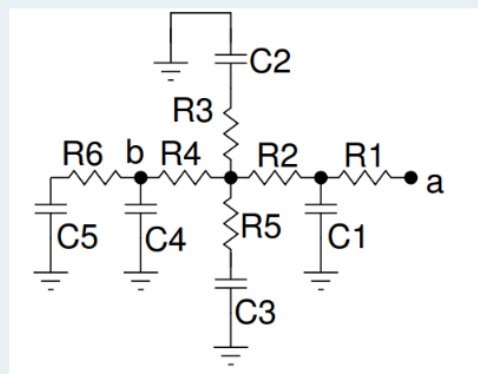
Path 3: $T_3 + (0 - t_{\text{skew2}}) > t_{\text{cq3}} + t_{\text{p,max}}(CL_3) + t_{\text{setup1}}$
 $T_3 > 150\text{p} + 700\text{p} + 50\text{p} + 50\text{p} = 950\text{p} \rightarrow 1.05\text{GHz}$

• So the critical path is Path 1 and the maximum frequency is 666MHz.

- Determine the Elmore delay from Node a to Node b in the following circuit

Question 2
Complete
Mark 0.00 out of 1.00
Flag question

Determine the Elmore delay from Node a to Node b in the following circuit



- ☒ A. delay = $R1(C1 + C2 + C3) + R2(C2 + C3 + C4) + R4(C4 + C5)$
- ☐ B. delay = $(R1 + R2 + R3 + R4)(C4 + C5)$
- ☒ C. delay = $R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$
- ☐ D. delay = $R1(C1 + C2 + C3 + C4) + R2(C2 + C3 + C4) + R4(C4 + C5)$

The correct answer is: delay = $R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$

- the below figure represents

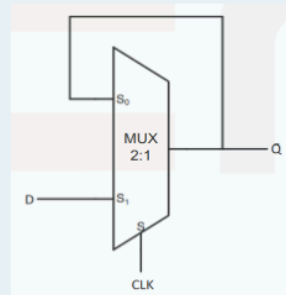
Question 6

Complete

Mark 0.00 out of 1.00

Flag question

the below figure represents



- ☐ A. static latch
- ☐ B. dynamic mux
- ☒ C. dynamic flip flop
- ☐ D. dynamic latch

The correct answer is: static latch

- What is the function $f(a,b,c,d)$?

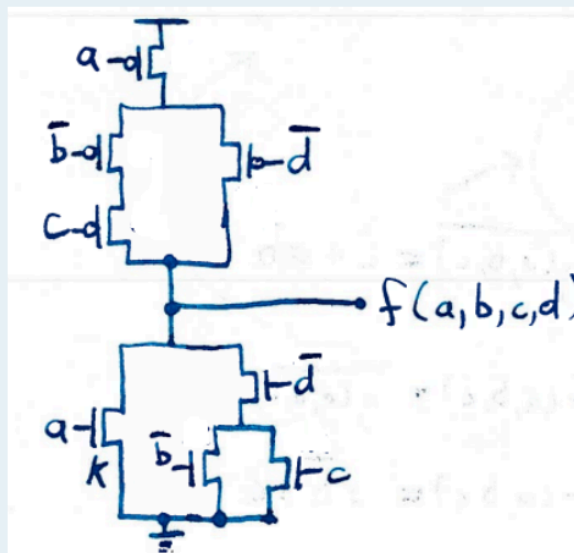
Question 1

Complete

Mark 1.00 out of 1.00

Flag question

What is the function $f(a,b,c,d)$?



- ☐ A. $F = a'(b'c' + d)$
- ☐ B. $F = a'bc' + d$
- ☐ C. $F = a(bc' + d)$
- ☐ D. $F = a'(bc + d')$
- ☒ E. $F = a'(bc' + d)$

-
- Threshold voltage increases for narrow NMOSFETs.

Question **2**

Complete

Mark 1.00 out of 1.00

🚩 Flag question

Threshold voltage increases for narrow NMOSFETs.

- ☒ True
☐ False

The correct answer is 'True'.

-
- Threshold voltage decreases for very short NMOSFETs

Question **3**

Complete

Mark 1.00 out of 1.00

🚩 Flag question

Threshold voltage decreases for very short NMOSFETs

- ☒ True
☐ False

The correct answer is 'True'.

-
- List the following interconnect fabrication steps in chronological order:

Question **4**

Complete

Mark 0.20 out of 1.00

🚩 Flag question

List the following interconnect fabrication steps in chronological order:

• Etch metal. • Expose photoresist using mask. • Remove all photoresist. • Deposit photoresist. • Deposit metal everywhere.

- 1) Deposit photoresist. ⌵
2) • Expose photoresist using mask. ⌵
4) Etch metal ⌵
3) Remove all photoresist. ⌵
5) Deposit metal everywhere ⌵

The correct answer is: 1) → Deposit metal everywhere, 2) → Deposit photoresist., 4) → Etch metal, 3) → • Expose photoresist using mask., 5) → Remove all photoresist.

- Consider the following transfer curve
- What are its NMH and NML?
- What is VM

Question 5

Complete

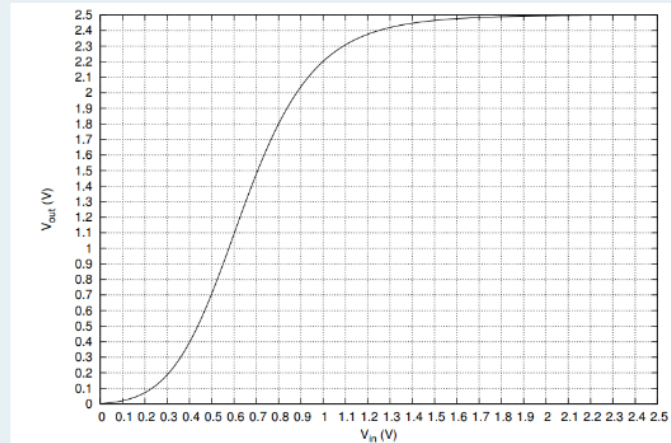
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Remove flag

Consider the following transfer curve

What are its NMH and NML?

What is VM



NMH \approx 1.5 V

NML \approx 0.25 V

VM \approx 0.77 V

- Report /Estimate NML and NMH for this technology. Consider the transfer function shown in the following figure.

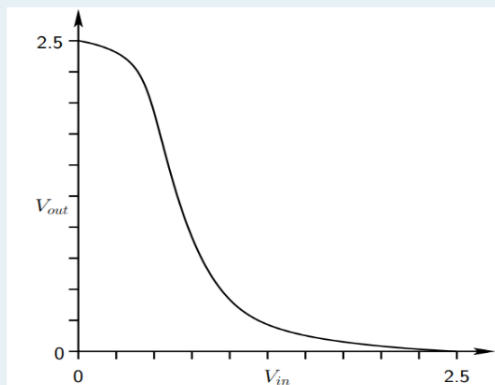
Question 6

Complete

Mark 1.00 out of 1.00

Flag question

Report /Estimate NML and NMH for this technology. Consider the transfer function shown in the following figure.



☒ A. NMH = 1.375 V

☒ B. NML = 0.375 V

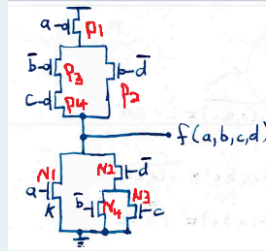
☐ C. NMH = 0.375 V

☐ D. NMH = 0.375 V

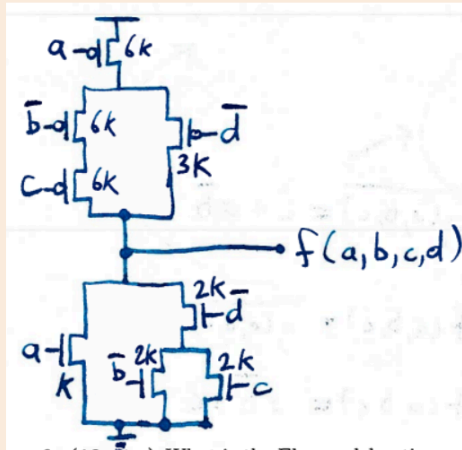
- Match each transistor size based on an inverter of 1k for NMOS and 2k for PMOS

Question 7
Complete
Mark 0.20 out of 1.00
Flag question

Match each transistor size based on an inverter of 1k for NMOS and 2k for PMOS



N2=
P5=
N4=
N5=
N3=
P3=
P2=
P4=
P1=
N1=



The correct answer is: N2= → 2k, P5= → 6k, N4= → 2k, N5= → 2k, N3= → 2k, P3= → 6k, P2= → 3k, P4= → 6k, P1= → 6k, N1= → 1k

- Consider the NMOS inverter given.
- $V_{DD} = 5\text{ V}$, $R_D = 22\text{ k}\Omega$
- $V_{tn} = 1.5\text{ V}$, $K_N = 100\text{ }\mu\text{A/V}^2$
- Determine $V_{OL(\min)}$ when $V_i = V_{DD}$
- Example for answer to be written $V_{OL(\min)} = 9.4\text{ v}$

Question 8

Complete

Mark 0.00 out of 1.00

Flag question

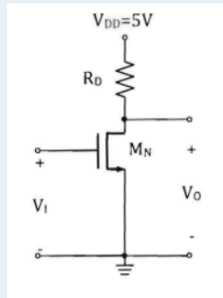
Consider the NMOS inverter given.

$V_{DD} = 5\text{ V}$, $R_D = 22\text{ k}\Omega$

$V_{tn} = 1.5\text{ V}$, $K_N = 100\text{ }\mu\text{A/V}^2$

Determine $V_{OL(\min)}$ when $V_i = V_{DD}$

Example for answer to be written **$V_{OL(\min)} = 9.4\text{ v}$**



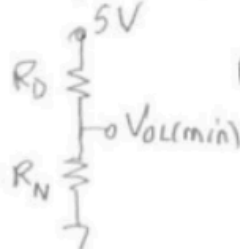
Answer: $V_{OL(\min)} = 1.5\text{ v}$

$$V_i = V_{DD} = 5\text{ V} \Rightarrow V_o = V_{OL(\min)}$$

Approximate method:

NMOS is NONSAT and

$$V_{OL(\min)} \ll V_i - V_{Tn}$$



$$R_n = \frac{1}{2K_N(V_{DD} - V_{GS})}$$

$$= \frac{1}{2(0.1\text{ mA/V}^2)(3.5\text{ V})}$$

$$= \frac{1}{0.7\text{ mA/V}} = 1.43\text{ k}\Omega$$

$$V_{OL(\min)} = \frac{R_N}{R_D + R_N} V_{DD} = \frac{1.43}{22 + 1.43} \cdot 5\text{ V}$$

$$V_{OL(\min)} = 0.3\text{ V} \ll V_i - V_{Tn} = 3.5\text{ V}$$

The correct answer is: $V_{OL(\min)} = 3.5\text{ v}$

- What is the output $F(a,b,c,d)$ for a given circuit shown below

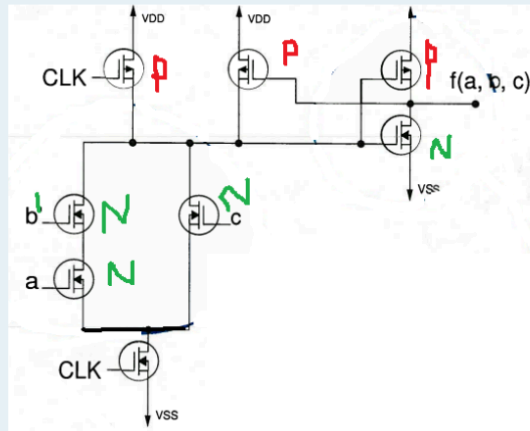
Question 9

Complete

Mark 1.00 out of 1.00

Flag question

What is the output $F(a,b,c,d)$ for a given circuit shown below



- ☒ A. $ab'+c$
- ☐ B. $ab+c$
- ☐ C. $a+b'.c$
- ☐ D. $ab'c$

- Derive an expression for the time constant when driving node d. V_s changes from 0 V to 2.5 V at time zero. (delay from s to d)

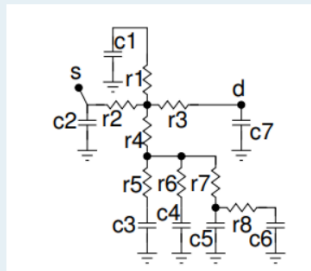
Question 10

Complete

Mark 1.00 out of 1.00

Flag question

Derive an expression for the time constant when driving node d. V_s changes from 0 V to 2.5 V at time zero. (delay from s to d)



- ☐ A. $\tau_d = r_2 (c_1 + c_3) + (r_2 + r_3 + c_4 + c_5 + c_6) c_7$.
- ☐ B. $\tau_d = r_2 (c_2 + r_3 + c_4 + c_5 + c_6) c_7$.
- ☒ C. $\tau_d = r_2 (c_1 + c_3 + c_4 + c_5 + c_6) + (r_2 + r_3) c_7$.
- ☐ D. $\tau_d = r_2 (c_1 + c_3 + c_4) + (r_2 + r_3 + c_5 + c_6) c_7$.

- Determine the Elmore delay from Node a to Node b in the following circuit

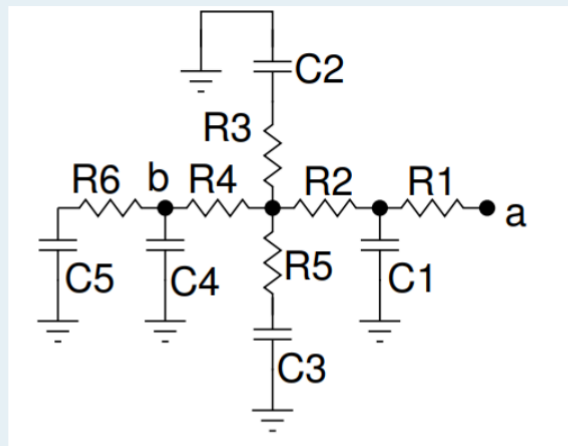
Question 11

Complete

Mark 0.00 out of 1.00

Flag question

Determine the Elmore delay from Node a to Node b in the following circuit



- ☐ A. delay = $(R1 + R2 + R3 + R4)(C4 + C5)$
- ☒ B. delay = $R1(C1 + C2 + C3 + C4) + R2(C2 + C3 + C4) + R4(C4 + C5)$
- ☐ C. delay = $R1(C1 + C2 + C3) + R2(C2 + C3 + C4) + R4(C4 + C5)$
- ☐ D. delay = $R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$

The correct answer is: delay = $R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$

- The PMOSFETs and NMOSFETs in an inverter have been sized to achieve balanced rise and fall times by making the NMOS larger than the PMOS .

Question 3

Complete

Mark 0.00 out of 1.00

Remove flag

The PMOSFETs and NMOSFETs in an inverter have been sized to achieve balanced rise and fall times by making the NMOS larger than the PMOS .

- ☒ True
- ☐ False

The correct answer is 'False'.

- List the following interconnect fabrication steps in chronological order:
- Etch metal. • Expose photoresist using mask. • Remove all photoresist. • Deposit photoresist. • Deposit metal everywhere

Question 4

Complete

Mark 1.00 out of 1.00

Flag question

List the following interconnect fabrication steps in chronological order:

• Etch metal. • Expose photoresist using mask. • Remove all photoresist. • Deposit photoresist. • Deposit metal everywhere.

- 3)
- 5)
- 2)
- 4)
- 1)

The correct answer is: 3) → Expose photoresist using mask., 5) → Remove all photoresist., 2) → Deposit photoresist., 4) → Etch metal, 1) → Deposit metal everywhere

- Consider the following transfer curve
- What are its NMH and NML?
- What is VM

Question 6

Complete

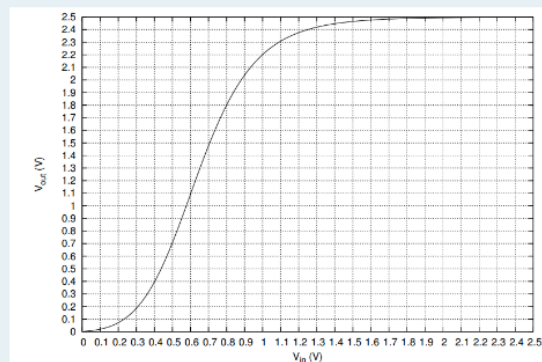
Mark 1.00 out of 1.00

Flag question

Consider the following transfer curve

What are its NMH and NML?

What is VM



- NMH \approx
- VM \approx
- NML \approx

The correct answer is: NMH \approx → 1.5 V, VM \approx → 0.77 V, NML \approx → 0.25 V

- Consider the NMOS inverter given.
- $V_{DD} = 5\text{ V}$, $R_D = 22\text{ k}\Omega$
- $V_{th} = 1.5\text{ V}$, $K_N = 100\text{ }\mu\text{A/V}^2$ Determine $V_{OL(min)}$ when $V_i = V_{DD}$ Example for answer to be written $V_{OL(min)} = 9.4\text{ V}$

Question 8

Complete
Mark 0.00 out of 1.00

Flag question

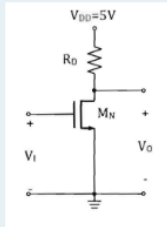
Consider the NMOS inverter given.

$V_{DD} = 5\text{ V}$, $R_D = 22\text{ k}\Omega$

$V_{th} = 1.5\text{ V}$, $K_N = 100\text{ }\mu\text{A/V}^2$

Determine $V_{OL(min)}$ when $V_i = V_{DD}$

Example for answer to be written $V_{OL(min)} = 9.4\text{ V}$



Answer: $V_{OL(min)} = 1.5\text{ V}$

$V_i = V_{DD} = 5\text{ V} \Rightarrow V_O = V_{OL(min)}$
Approximate method:
 NMOS is in saturation and
 $V_{OL(min)} \ll V_i - V_{th}$
 $R_D = 22\text{ k}\Omega$
 $R_N = \frac{1}{2K_N(V_{DD} - V_{th})} = \frac{1}{2(0.1\text{ mA/V}^2)(5\text{ V})} = \frac{1}{0.7\text{ mA/V}} = 1.43\text{ k}\Omega$
 $V_{OL(min)} = \frac{R_N}{R_D + R_N} V_{DD} = \frac{1.43}{22 + 1.43} \cdot 5\text{ V}$
 $V_{OL(min)} = 0.3\text{ V} \ll V_i - V_{th} = 3.5\text{ V}$

The correct answer is: $V_{OL(min)} = 3.5\text{ V}$

- holes generally travel more slowly than electrons in IC semiconductors.

Question 3

Complete
Mark 1.00 out of 1.00

Flag question

holes generally travel more slowly than electrons in IC semiconductors.

- ☒ True
☐ False

Use up to two sentences to explain why holes generally travel more slowly than electrons in IC semiconductors. Took multiple answers, e.g., "higher particle mass for holes than electrons" or "more likely interaction with holes and semiconductor lattice results in higher probability of change in particle direction"

The correct answer is 'True'.

- In the following circuit, the capacitance of C_L is 50 fF.
- C_L is initially charged to 2.5 V. At time zero, its gate is attached ground, as shown in the figure. $V_{TP} = -0.5$ V.
- 1) If we replace the PMOSFET with a 2 k Ω resistor, how long does it take for the capacitor to discharge to 1.25 V? *Your answer should be like this (1) 120ps)*
- 2) If we consider the transistor cut-off, what is the final voltage of the capacitor?
- *Your answer should be like this (2) 200v)*

Question 6

Complete

Mark 0.00 out of 1.00

[Remove flag](#)

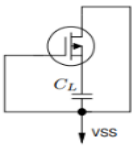
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1) If we replace the PMOSFET with a 2 k Ω resistor, how long does it take for the capacitor to discharge to 1.25 V? *Your answer should be like this (1) 120ps)*

2) If we consider the transistor cut-off, what is the final voltage of the capacitor?

Your answer should be like this (2) 200v)



PMOSFET with grounded gate.

☒ A. 1) 9ps

☐ B. 2) 0.5v

☐ C. 1) 0.69ps

☐ D. 1) 69ps

☒ E. 2) 2.25v

☐ F. 2) 2.5v

☐ G. 2) 2.0v

$$2.5 \text{ V} / 2 = 2.5 \text{ V} \cdot e^{\frac{-t}{100 \text{ ps}}}$$

$$1/2 = e^{\frac{-t}{100 \text{ ps}}}$$

$$\log 1/2 = \frac{-t}{100 \text{ ps}}$$

$$0.69 = \frac{t}{100 \text{ ps}}$$

$$t = 69 \text{ ps}$$

- Temperature does not affect RC of the wire ?

Temperature does not affect RC of the wire ?

☐ True

☒ False

The correct answer is 'False'.

- The data doesn't have enough time to pass from one register to the next before the next clock edge.

----- The data doesn't have enough time to pass from one register to the next before the next clock edge.

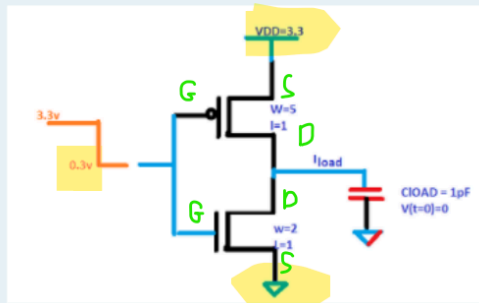
- ☐ A. NA
- ☐ B. Min Delay
- ☒ C. Max Delay
- ☐ D. Buffer delay

The correct answer is: Max Delay

- A step input is applied at time $t=0$ to the loaded inverter with dimensions and initial conditions as shown below.

A step input is applied at time $t=0$ to the loaded inverter with dimensions and initial conditions as shown below.

For all transistors: $L_{min} = 1 \mu m$, $W_{min} = 1 \mu m$, $V_{T,p} = -1 V$, $\mu_p C_{ox} = (1/6) \times 10^{-3} A/V^2$, $\lambda_p = 0.0V^{-1}$, $V_{T,n} = 1 V$, $\mu_n C_{ox} = (1/2) \times 10^{-3} A/V^2$, $\lambda_n = 0.0V^{-1}$.



What region the PMOS will be in? (Linear, Cutoff, Saturation)

Saturation ✓

What region the NMOS will be in?

Cutoff ✓

What is the current I_{load} immediately after the step is applied in mA?

1.67 ✓

Note: do not add a unit, just the number

Your answer is correct.

$$\begin{aligned} \text{PMOS: } V_{GS} &= -3V \quad V_{DS} = -3.3V \\ V_{GS} - V_{T,p} &= -2V > V_{T,p} \quad \text{Saturation} \\ \text{NMOS: } V_{GS} &= 0.3V < V_{T,n} = 1V \quad \text{cutoff} \\ I_L &= I_{NMOS} = \frac{\mu_n C_{ox}}{2} \left(\frac{W}{L} \right) (V_{GS} - V_{T,n})^2 \\ &= \frac{(1/2 \times 10^{-3} A/V^2)}{2} \left(\frac{5}{1} \right) (-2.0V - (-1V))^2 \\ &= \boxed{1.67 \mu A} \quad (0.5 \mu A) \end{aligned}$$

The correct answer is:

What region the PMOS will be in? (Linear, Cutoff, Saturation) → Saturation,

What region the NMOS will be in? → Cutoff,

What is the current I_{load} immediately after the step is applied in mA?

Note: do not add a unit, just the number → 1.67

- Some of advantages of IC are :

Question 4

Complete

Marked out of 1.00

Some of advantages of IC are :

- ☐ A. Cost is High
- ☐ B. Design Complexity is large
- ☒ C. High Speed
- ☒ D. Less Power Dissipation
- ☒ E. Size is less

- Match to the correct answer
- Performance
- Area
- Body (substrate) normally connected

Match to the correct answer

Performance

Area

Body (substrate) normally connected to ----- for NMOS

The interface between designer and process (CMOS fabrication) engineer used in chip manufacturing

Raising source voltage increases ----- of transistor

Directly affects cost	↕	✗
Directly affects cost	↕	✓
Power-Delay Product	↕	✗
Design Rules	↕	✓
Silicon	↕	✓
Threshold Voltage	↕	✓

Your answer is partially correct.

You have correctly selected 4.

The correct answer is:

Performance → Power-Delay Product,

Area → Directly affects cost,

Body (substrate) normally connected to ----- for NMOS → Threshold Voltage,

The interface between designer and process (CMOS fabrication) engineer → Design Rules,

used in chip manufacturing → Silicon,

Raising source voltage increases ----- of transistor → Threshold Voltage

- Which is faster Holes or Electrons?

Question 8

Correct

Mark 1.00 out of 1.00

Flag question

Which is faster Holes or Electrons?

Answer: Electrons ✓

- Increasing fan-out, INCREASE OR DECREASES the propagation delay
-

Question 9

Correct

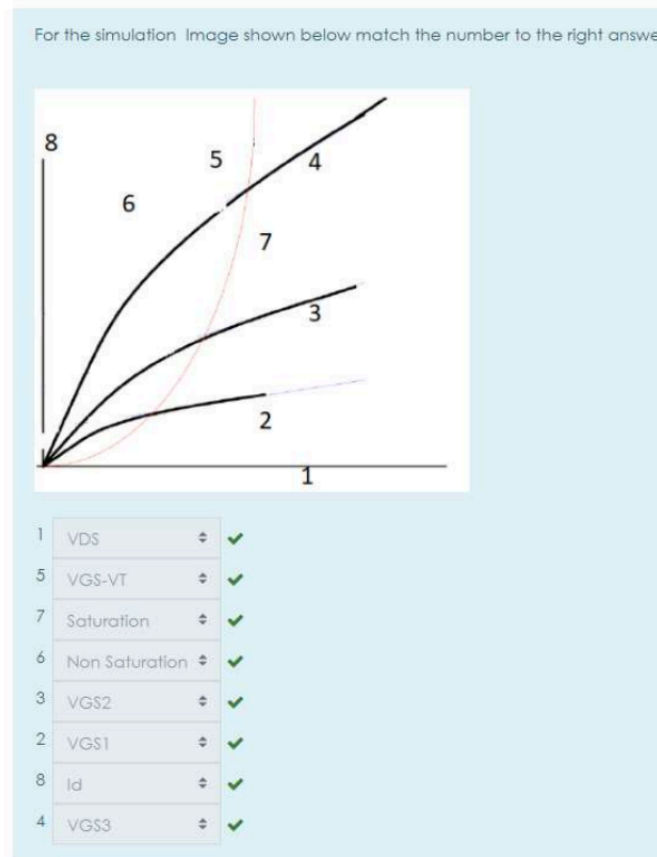
Mark 1.00 out of 1.00

Flag question

Increasing fan-out, INCREASE OR DECREASES the propagation delay

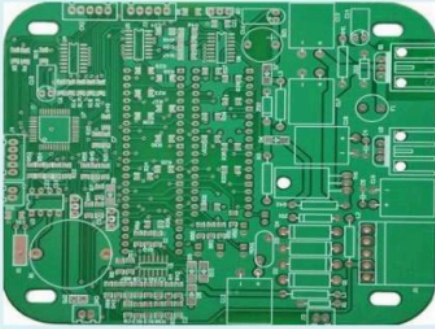
Answer: INCREASE ✓

- For the simulation Image shown below match the number to the right answer

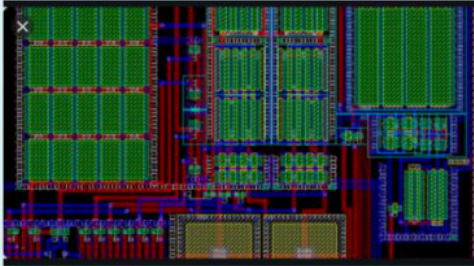


- Match the right name to the image

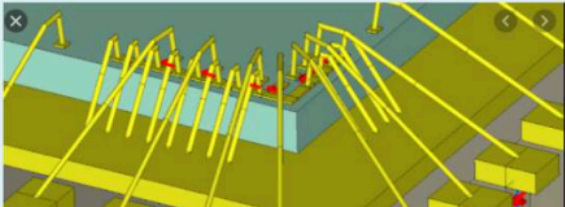
Match the right name to the image



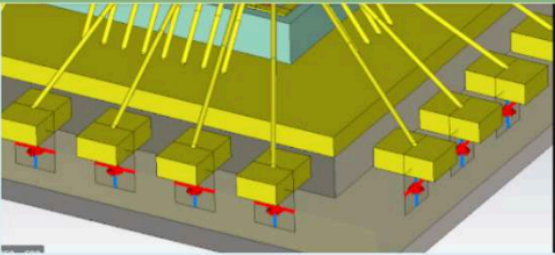
PCB Board ✓



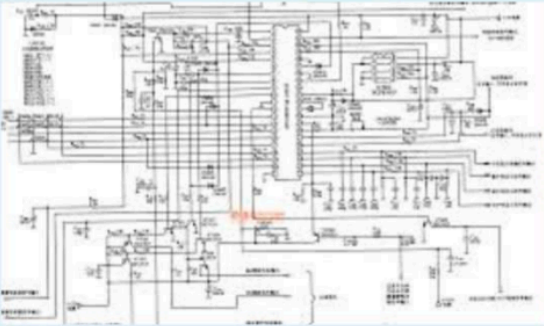
IC layout ✓



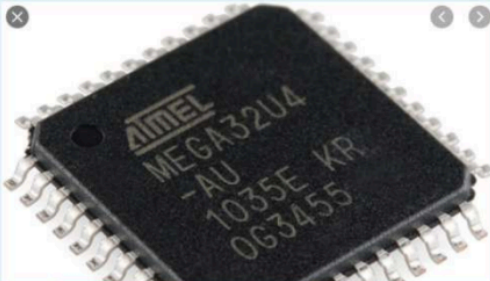
IC Package ✓



IC Package ✓



IC schematic ✓



Chip or IC ✓

- Threshold voltage is negative for

Question 12

Incorrect

Mark: 0.00 out of 1.00

Flag question

Threshold voltage is negative for

Select one:

- ☒ a. pMOS depletion ✖
- ☐ b. nMOS depletion

- ID and threshold voltage

Question 13

Correct

Mark: 4.00 out of 4.00

Flag question

ID and threshold voltage

I_{ds} is to length ----- L of the channel

When the threshold voltage is more, leakage current will be

In saturation mode, MOSFET is used as

inversely proportional

less

current source

✓

✓

✓

- There are _____ of operations for MOSFET

Question 14

Correct

Mark: 1.00 out of 1.00

Flag question

SELECT ALL THAT APPLY . There are ----- of operations for MOSFET

Select one:

- ☐ a. 2 REGIONS
- ☐ b. NO REGION
- ☒ c. 3 REGIONS ✓
- ☐ d. 1 REGION
- ☐ e. 5 REGION

- The current I_{ds} _____ as V_{ds} increases in the saturation region

Question 15

Correct

Mark 1.00 out of 1.00

Flag question

The current I_{ds} _____ as V_{ds} increases in the saturation region

Select one:

- ☐ a. increases
- ☐ b. exponentially increases
- ☐ c. decreases
- ☒ d. remains fairly constant ✓

- CMOS technology is used in developing

CMOS technology is used in developing _____

Select one:

- ☐ a. metal layer
- ☐ b. does not used to for microprocessor
- ☒ c. digital logic circuits ✓

- I_{ds} versus V_{ds} Relationships

I_{ds} versus V_{ds} Relationships

electric field(E_{ds}) is given by

V_{ds} / L ✓

I_{ds} depend on

V_{gs} and V_{ds} ✓

Velocity can be given as

μ / E_{ds} ✓

The condition for saturation is

$V_{ds} = V_{gs} - V_t$ ✓

- In CMOS fabrication, the photoresist layer is exposed to _____

In CMOS fabrication, the photoresist layer is exposed to ---

Select one:

- ☐ a. visible light
- ☒ b. ultraviolet light ✓
- ☐ c. infra red light
- ☐ d. no light at all

- What does output F equal base on the circuit below?

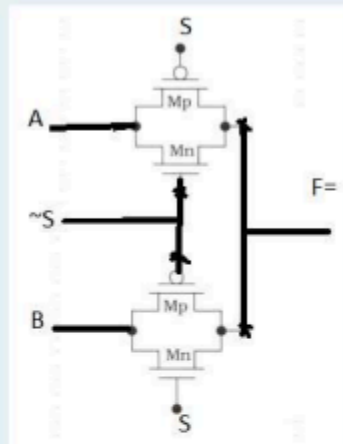
Question 1

Complete

Mark 1.50 out of 1.50

Flag question

What does output **F** equal base on the circuit below?



- ☐ a. $(S.A) + (\sim S.B)$
- ☐ b. $(\sim S.A) + (\sim S.B)$
- ☒ c. $(\sim S.A) + (S.B)$
- ☐ d. $(\sim S.A) + (S.\sim B)$
- ☐ e. $(S.A) + (S.B)$

The correct answer is:
 $(\sim S.A) + (S.B)$

- Based on the devices shown below, answer the following questions

Question 2
Complete
Mark: 4.00 out of 4.00
Flag question

Based on the devices shown below, answer the following questions :

$V_{y2} =$

 $V_{p2} =$

 $V_{p1} =$

 $V_y =$

- Given the Image below to represent IC design flow , match the number to the right step name

Question 3
Complete
Mark: 2.00 out of 2.00
Flag question

Given the Image below to represent IC design flow , match the number to the right step name

Fabrication

 In step 1, what does the left picture represent

 Packaging

 Physical Design

The correct answer is:
 Fabrication → 2,
 In step 1, what does the left picture represent → top level cell view,
 Packaging → 3,
 Physical Design → 1

- Based on the cross-section shown below, map each letter to the right name

Question 4
Complete
Mark 4.50 out of 4.50
Flag question

Based on the cross-section shown below, map each letter to the right name

D substrate

C NMOS-device

Z VDD

X GND

A Poly

Y output

the cross-section represent Inverter

B PMOS-Device

- Given the image below, answer the following questions

Question 5
Complete
Mark 3.00 out of 3.00
Flag question

Given the image below, answer the following questions

How many dies are there? 22

what is the defect % ? 12/22

your answer should be In this form 13/40

How many wafer we have in the picture 1

- Based on the structure shown below which N tree you connect to which P tree to form this function

Question 6
Complete
Mark 3.00 out of 3.00
Flag question

Based on the structure shown below which N tree you connect to which P tree to form this function

$f = a \cdot (b + c \cdot (d + e))$

☐ a. P2 with N3
☐ b. P2 with N1
☐ c. P1 with N1
☐ d. P1 with N2
☒ e. P3 with N3
☐ f. P1 with N3
☐ g. P3 with N2

- Given physical design below what will be the value for X and Y ?

Question 7
Complete
Mark 0.00 out of 2.00
Flag question

Given physical design below what will be the value for X and Y ?

$X = \neg(A \text{ OR } B)$
 $Y = \neg(A \text{ OR } B)$

The correct answer is:
 $X = \neg A$
 $Y = \neg B$

- Given the design shown below, answer the following questions

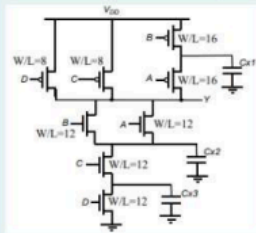
Question 8

Complete

Mark: 0.00 out of 5.00

Flag question

Given the design shown below, answer the following questions



are the devices sized correctly giving that the output resistance is the same as that of an inverter with an NMOS W/L = 4 and PMOS W/L = 8,

no

What is the logic function implemented by the CMOS transistor network?

$Y = \sim((AB), C+D)$

What are the VALUES OF THE INTERNAL NODES caps that give the best-case tpHL

tpHL happens when the internal node capacitances (Cx2 and Cx3) are charged before the high to low transition

which has a bigger cap Cx1 or Cx2, ignore material type factor

cx1

The correct answer is:

are the devices sized correctly giving that the output resistance is the same as that of an inverter with an NMOS W/L = 4 and PMOS W/L = 8. → yes,

What is the logic function implemented by the CMOS transistor network? → $Y = (\sim A + \sim B) \cdot (\sim C + \sim D)$,

What are the VALUES OF THE INTERNAL NODES caps that give the best-case tpHL → tpHL happens when the internal node capacitances (Cx2 and Cx3) are discharged before the high to low transition,

which has a bigger cap Cx1 or Cx2, ignore material type factor → cx2

- Fabrication Steps

Question 9

Complete

Mark: 2.00 out of 2.00

Flag question

Fabrication Steps

Spin on photoresist

Photoresist

Expose photoresist through n-well mask

Lithography

Grow SiO2 on top of Si wafer

Oxidation

Polysilicon

Deposit very thin layer of gate oxide

The correct answer is:

Spin on photoresist → Photoresist,

Expose photoresist through n-well mask → Lithography,

Grow SiO2 on top of Si wafer → Oxidation,

Polysilicon → Deposit very thin layer of gate oxide

- Given that $R_p/R_n=3$ size the following circuit TO HAVE EQUAL T_r and T_f accordingly

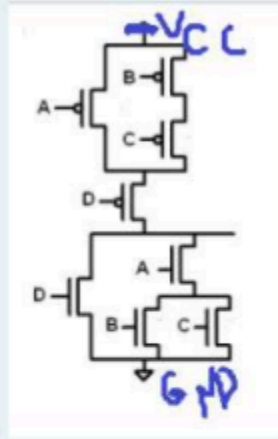
Question 10

Complete

Mark 1.50 out of 3.00

Flag question

Given that $R_p/R_n=3$ size the following circuit TO HAVE EQUAL T_r and T_f accordingly



D-Pdevice	6	↕
B-Pdevice	12	↕
B-Ndevice	6	↕
A-Pdevice	6	↕
A-Ndevice	6	↕
D-Ndevice	3	↕

The correct answer is:

D-Pdevice $\rightarrow 18$,

B-Pdevice $\rightarrow 36$,

B-Ndevice $\rightarrow 6$,

A-Pdevice $\rightarrow 18$,

A-Ndevice $\rightarrow 6$,

D-Ndevice $\rightarrow 3$

- When the channel pinches off?

When the channel pinches off?

Select one:

- ☐ a. $V_{gs} > V_{ds}$
- ☐ b. $V_{ds} > V_{gs}$
- ☒ c. $V_{ds} > (V_{gs} - V_{th})$ ✓
- ☐ d. $V_{gs} > (V_{ds} - V_{th})$

- Match the number to the right IC design step/process

Question 2
Partially correct
Mark 1.00 out of 3.00
Flag question

Match the number to the right IC design step/process

3 RTL design ✓
6 Idea/Specification ✓
2 simulation ✗
1 physical design ✗
4 synthesis ✗
7 Functional Verification ✗

- in chip design. Lithography is

Question 3
Correct
Mark 1.00 out of 1.00
Flag question

In chip design, Lithography is -----

Select one:

☒ a. Process used to transfer a pattern to a layer on the chip ✓
☐ b. Process used to develop an oxidation layer on the chip
☐ c. Process used to develop a metal layer on the chip
☐ d. Process used to produce the chip

- Match the right answers
 - MOSFET need _____ to be characterized
 - The _____ is not part of device characteristics
 - MOSFETs have _____

Question 4
Partially correct
Mark 2.25 out of 3.00
Flag question

Match the right answers

MOSFET need -----to be characterized two sets of current-voltage curves ✓
 ----- two sets of current-voltage curves ✗
 The ----- is not part of device characteristics gate current ✓
 MOSFETs have ----- four terminals ✓

- NMOS devices

Question 5

Correct

Mark 5.00 out of 5.00

Flag question

NMOS devices

In n channel MOSFET, _____ is constant	channel length ✓
Source and drain in nMOS device are isolated by	diodes ✓
NMOS devices are formed in	p-type substrate of moderate doping level ✓
Interconnection pattern is made on	metal layer ✓
In nMOS device, gate material could be	polysilicon ✓

- Select the right schematic for the cross-section given below

Question 7

Correct

Mark 3.00 out of 3.00

Flag question

Select the right schematic for the cross-section given below

-
- In CMOS fabrication, nMOS and pMOS are integrated in the same substrate

In CMOS fabrication, nMOS and pMOS are integrated in the same substrate

Select one:

- ☒ True ✓
- ☐ False

-
- Goal of library cell Characterization:

Question 30
Not yet
answered
Marked out of
1.00
Flag
question

Goal of library cell Characterization:

- ☐ a. performed for various combinations of operating conditions: process, voltage, temperature (also called PVT corners).
- ☐ b. . None
- ☒ c. A and B
- ☐ d. computes cell parameter like delay, output current depending on load, Input slew

[Clear my choice](#)

-
- System on chip means

Question 1

Complete

Mark 1.00 out
of 1.00

Flag
question

System on chip means

Select one:

- ☒ a. It consists of both analog and digital IC
- ☐ b. It consists analog IC
- ☐ c. It consists digital IC only
- ☐ d. None of them is true

- Uploaded By: Amr Halahla

- n-type semiconductors are

Question 4
Complete
Mark 0.00 out of 1.00
Flag question

n-type semiconductors are

Select one:

- ☐ a. None of them
- ☐ b. Negatively charged
- ☐ c. Positively charged
- ☒ d. Neutral charged

- The packaging is used in IC for

Question 5
Complete
Mark 1.00 out of 1.00
Flag question

The packaging is used in IC for

Select one:

- ☒ a. safety and protection
- ☐ b. power delivery to each circuit
- ☐ c. none of them
- ☐ d. wire local blocks

- Indicate whether each of the following has been increasing or decreasing with process scaling for synchronous integrated circuits.

Question 6
Complete
Mark 2.00 out of 2.00
Flag question

Indicate whether each of the following has been increasing (↑) or decreasing (↓) with process scaling for synchronous integrated circuits.

tax

decreasing ↓

Power consumption per device per switching event

decreasing ↓

Clock frequency

increasing ↑

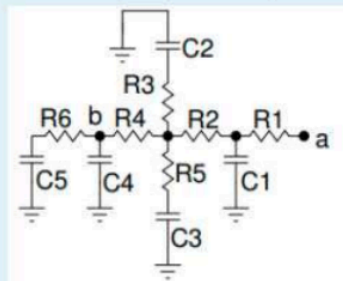
Dynamic power consumption as a proportion of total power consumption

decreasing ↓

- Determine the Elmore delay from Node a to Node b in the following circuit.

Question 7
Complete
Mark 2.00 out of 2.00
Flag question

Determine the Elmore delay from Node a to Node b in the following circuit.



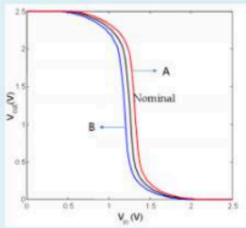
Select one:

- ☐ a. $\tau_{ab} = R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4)$
- ☒ b. $\tau_{ab} = R1(C1 + C2 + C3 + C4 + C5) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$
- ☐ c. $\tau_{ab} = R1(C1 + C2 + C3 + C4) + R2(C2 + C3 + C4 + C5) + R4(C4 + C5)$
- ☐ d. $\tau_{ab} = R1(C1 + C2 + C3 + C5) + R2(C2 + C3 + C5) + R4(C4 + C5)$

- The PMOSFETs and NMOSFETs in an inverter have been sized to achieve balanced rise and fall times. However, process variation has caused the implementation to deviate from the design. The A line in Figure below is associated with an inverter that has

Question 8
Complete
Mark 2.00 out of 2.00
Flag question

The PMOSFETs and NMOSFETs in an inverter have been sized to achieve balanced rise and fall times. However, process variation has caused the implementation to deviate from the design. The A line in Figure below is associated with an inverter that has



Select one:

- ☒ a. Lower-than-planned resistance PMOSFET and higher-than-planned resistance NMOSFET.
- ☐ b. Higher-than-planned resistance PMOSFET and lower-than-planned resistance NMOSFET.
- ☐ c. no change of resistance for PMOSFET and resistance of NMOSFET.

- The mobility is given by:

Question 9
Complete
Mark 1.00 out of 1.00
Flag question

The mobility is given by :

Select one:

- ☐ a.
- ☒ b.
- ☐ c.

$\mu = E_0 / V_0$

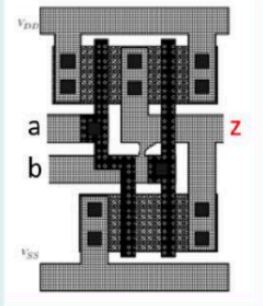
$\mu = V_0 / E_0$

$\mu = E_0 \cdot V_0$

- A dust particle did something horrible to a mask, causing the implemented layout to differ from the designed layout. Consider the corrupted layout shown in Figure below

Question 10
Complete
Mark 3.00 out of 3.00
Flag question

A dust particle did something horrible to a mask, causing the implemented layout to differ from the designed layout. Consider the corrupted layout shown in Figure below



is there any input vector (a, b) for which the output and power consumption will be as the designer originally intended? if so, indicate the input vector

What type of gate was the designer most likely trying to implement?

If you draw a schematic for the gate actually implemented, then

a'b

NAND2

input b shorted to output z

- Stick diagrams are those which convey layer information through?

Question 11

Complete

Mark 1.00 out of 1.00

Flag question

Stick diagrams are those which convey layer information through?

Select one:

- ☐ a. thickness
- ☒ b. color
- ☐ c. shape
- ☐ d. design rules

- CMOS domino logic can be expressed diagrammatically as

Question 12

Complete

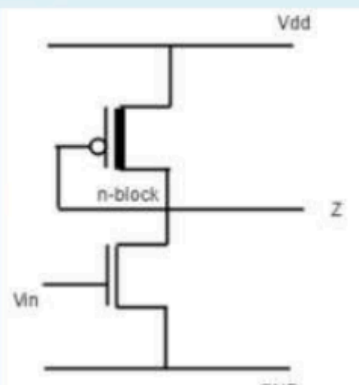
Mark 1.00 out of 1.00

Flag question

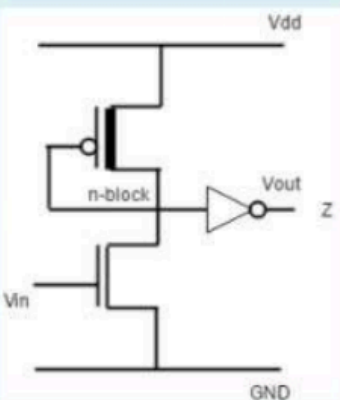
CMOS domino logic can be expressed diagrammatically as

Select one:

☒ a.



☐ b.



- How is nMOS depletion-mode transistor represented? given that diffusion is green, poly is red and well is dotted yellow line

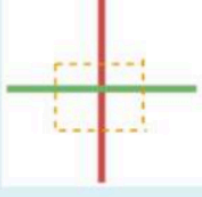
Question 13
Complete
Mark 0.00 out of 1.00
Flag question

How is nMOS depletion-mode transistor represented? given that diffusion is green, poly is red and well is dotted yellow line

Select one:

☐ a. 

☒ b. 

☐ c. 

- Which contributes to the wiring capacitance?

Question 14
Complete
Mark 1.00 out of 1.00
Flag question

Which contributes to the wiring capacitance?

Select one:

☐ a. interlayer capacitance

☐ b. fringing fields

☒ c. all of the mentioned

☐ d. peripheral capacitance

- Which has a high voltage drop?

Question 16
Complete
Mark 1.00 out of 1.00
Flag question

Which has a high voltage drop?

Select one:

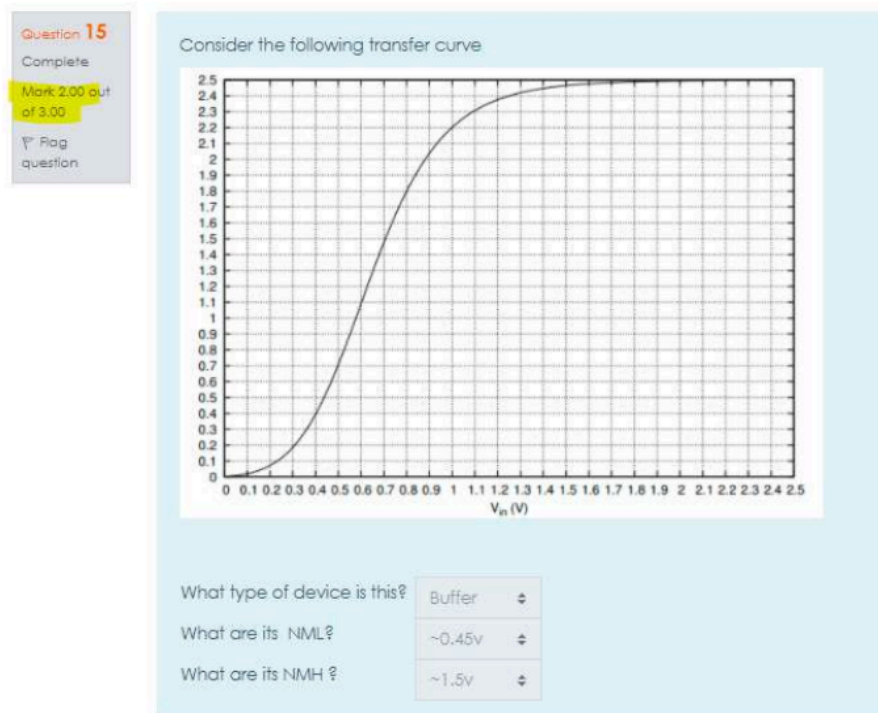
☐ a. metal 6 layer

☐ b. metal layer

☒ c. polysilicon layer

☐ d. diffusion layer

- Consider the following transfer curve



- Match to the correct answer
 - Threshold voltage is negative for
 - Two metal layers can be joined by using
 - When polysilicon crosses a diffusion
 - will be formed

Question 17
Complete
Mark 3.00 out of 3.00
Flag question

Match to the correct answer

Threshold voltage is negative for _____ pmos

Two metal layers can be joined by using via

When polysilicon crosses a diffusion _____ will be formed transistor

- The overall delay is ___ to the relative resistance r .

Question 19
Complete
Mark 1.00 out of 1.00
Flag question

The overall delay is ___ to the relative resistance r .

Select one:

☐ a. exponentially proportional

☐ b. inversely proportional

☒ c. directly proportional

- Match to correct answer
 - In resistive (linear) region
 - When the threshold voltage is more, leakage current will be?
 - When the channel pinches off?

Question 18

Complete

Mark 3.00 out of 3.00

Flag question

Match to correct answer

In resistive (linear) region _____

When the threshold voltage is more, leakage current will be?

When the channel pinches off?

$V_{ds} < (V_{gs} - V_t)$

less

$V_{ds} > (V_{gs} - V_{th})$

- Match to the correct answer/choice
 - In CMOS logic circuit the n-MOS transistor acts as:
 - Register cell consists of
 - The size of a transistor is usually defined in terms of its process based on

Question 20

Complete

Mark 1.00 out of 1.00

Flag question

Match to the correct answer/choice

In CMOS logic circuit the n-MOS transistor acts as:

Register cell consists of

The size of a transistor is usually defined in terms of its process based on

Pull down network

Inverter & pass transistor

channel length

- match/selec the right answer
 - Time, before the latch closes, that the data must arrive to guarantee the data is captured correctly after the latch closes
 - The transistor current changes with the operating temperature, as T increases mobiity
 - ff is the time taken for a waveform to fall from 90% to 10% of its steady-state value.

Question 21

Complete

Mark 3.00 out of 3.00

Flag question

match/selec the right answer

Time, before the latch closes, that the data must arrive to guarantee the data is captured correctly after the latch closes

The transistor **current changes** with the operating temperature, as T increases mobility _____ and I_{ds} _____

_____ ff is the time taken for a waveform to fall from 90% to 10% of its steady-state value.

Setup time

decreases, decreases

Fall time

- match to the right answer
 - Dynamic dissipation due to
 - Static dissipation due to _____ continuously from the power supply.
 - What are the advantages of the CMOS process
 - which is better for reducing dynamic power
 - increasing activity factor will _____ power

Question 22

Complete

Mark 4.00 out of 5.00

Flag question

match to the right answer

Dynamic dissipation due to

Static dissipation due to _____ continuously from the power supply.

What are the advantages of the CMOS process

which is better for reducing dynamic power

Increasing activity factor will _____ power

Charging and discharging of load capacitances

leakage current or other current drawn

Low power Dissipation

reducing clock

Increase

- Main Issues In Dynamic Design

Main Issues In Dynamic Design

☐ a. none

☒ b. All mentioned

☐ c. noise Issue

☐ d. High power

☐ e. Charge Leakage

Clear my choice

- Usually in IC design, the late signal (slow) will be connected:

Usually in IC design, the late signal (slow) will be connected:

☐ a. Ignored

☐ b. GND

☐ c. VCC

☒ d. close to output node

Clear my choice

-
- What is the various Silicon wafer Preparation?

What is the various Silicon wafer Preparation?

- ☐ a. Crystal growth & doping
- ☐ b. Wafer polishing & etching
- ☒ c. All mentioned
- ☐ d. Wafer cleaning

-
- What are the advantages of CMOS process?

What are the advantages of CMOS process?

- ☐ a. None is True
- ☐ b. All true
- ☒ c. Low power Dissipation
- ☐ d. High delay Sensitivity to load.

-
- Which MOS can pass logic1 and logic 0 stongly?

Which MOS can pass logic1 and logic 0 stongly?

- ☐ a. p-mos can pass strong logic 0, n-mos can pass strong logic 1
- ☒ b. p-mos can pass strong logic 1, n-mos can pass strong logic 0
- ☐ c. NONE

-
- I_{ds} depends on _____

I_{ds} depends on _____

- ☐ a. V_{ss}
- ☐ b. V_{dd}
- ☐ c. V_g
- ☒ d. V_{ds}

-
- Design rules does not specify _____

Design rules does not specify _____

- ☒ a. color of each layer
- ☐ b. Line widths
- ☐ c. Separations/spaces
- ☐ d. extensions

-
- In basic inverter circuit _____ is connected to ground

In basic inverter circuit _____ is connected to ground

- ☐ a. gate
- ☒ b. source
- ☐ c. drain

-
- Which among the following is a process of transforming design entry information of the circuit into a set of logic equations?

Which among the following is a process of transforming design entry information of the circuit into a set of logic equations?

- ☐ a. Verification
- ☐ b. Simulation
- ☐ c. Optimization
- ☒ d. Synthesis

- =====
- which process deals with the determination of resistance & capacitance of interconnections?

which process deals with the determination of resistance & capacitance of interconnections?

- ☐ a. Placement
- ☒ b. Extraction
- ☐ c. Floorplanning
- ☐ d. Routing

- =====
- Which type of digital systems exhibit the necessity for the existence of at least one feedback path from output to input?

Which type of digital systems exhibit the necessity for the existence of at least one feedback path from output to input?

- ☒ a. Sequential system
- ☐ b. none
- ☐ c. Combinational System

- =====
- The time required for an Input data to settle _____ the triggering edge of clock is known as 'Setup Time'.

The time required for an Input data to settle _____ the triggering edge of clock is known as 'Setup Time'.

- ☐ a. ALL are correct
- ☐ b. After
- ☐ c. During
- ☒ d. Before

- =====
- Hold time is defined as the time required for the data to _____ after the triggering edge of clock.

Hold time is defined as the time required for the data to _____ after the triggering edge of clock.

- ☒ a. Remain stable
- ☐ b. Increase
- ☐ c. Decrease

- =====
- ICs are generally made of

ICs are generally made of

- ☒ a. Silicon
- ☐ b. , None
- ☐ c. Germanium
- ☐ d. Copper

- =====
- Dynamic power:

Dynamic power:

- ☐ a. change linearly with voltage
- ☒ b. depends on the load capacitance
- ☐ c. Is not affected by frequency
- ☐ d. all mentioned

- =====
- For Standard Cell Physical Structure layout

For Standard Cell Physical Structure layout

- ☐ a. none
- ☒ b. All the cells in the library are designed to be multiple to unit tile
- ☐ c. , only first row of cell library are designed to be multiple to unit tile
- ☐ d. Placement uses vertical grid only in which cells are placed

- =====
- The design flow of IC design system is : 1. architecture design 2. market requirement 3. Layout 4. HDL coding 5. logic design

The design flow of IC design system is :

1. architecture design 2. market requirement 3. Layout 4. HDL coding 5. logic design

- A. 5-1-2-4-3
- B. 2-1-5-3-4
- C. 2-1-5-4-3
- D. 4-1-3-2-5
- E. 5-3-2-1-4

- =====
- CMOS NAND gate is better than CMOS NOR gates because

CMOS NAND gate is better than CMOS NOR gates because

- A. CMOS nor takes more space than NAND
- B. CMOS NOR uses P channel transistor in parallel.
- C. CMOS NAND uses P channel transistor in parallel.
- D. Only A and C is correct.
- E. All (A and B and C) are correct

- =====
- How many transistors are required to implement a four-input OR using CMOS design style?

How many transistors are required to implement a four-input OR using CMOS design style?

- A. 6
- B. 8
- C. 10
- D. 12
- E. None
- =====

- In order to have "pass" logic gate We need

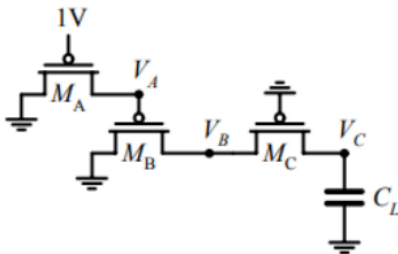
In order to have "pass" logic gate We need

- A. An N-channel and P-Channel transistor in series
- B. We need only p-channel so it will pass good one.
- C. We need only N-channel so it will pass good zero.
- D. An N-channel and P-Channel transistor in parallel**
- E. None

- For the circuit in Fig. below, determine the final value of V_A , V_B , V_C , assuming initial condition at each of the nodes is 3V and $V_{TP} = -0.5V$ (ignore body effect).

For the circuit in Fig. below, determine the final value of V_A , V_B , V_C , assuming initial condition at each of the nodes is 3V and $V_{TP} = -0.5V$ (ignore body effect).

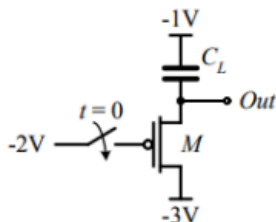
- A. $V_A = 3V$ $V_B = 2V$ $V_C = 1.5V$
- B. $V_A = 1.5V$ $V_B = 1.5V$ $V_C = 1.5V$
- C. $V_A = 2V$ $V_B = 2V$ $V_C = 2V$
- D. $V_A = 1.5V$ $V_B = 2V$ $V_C = 2V$**
- E. None



- Assuming that switch as shown in figure below closes at time $t = 0$, what is the output voltage at $t = 0+$ and $t = \infty$? C_L was initially discharged, $V_{TP} = -0.5V$.

6. Assuming that switch as shown in figure below closes at time $t = 0$, what is the output voltage at $t = 0+$ and $t = \infty$? C_L was initially discharged, $V_{TP} = -0.5V$.

- A. $V_{out}(t = 0+) = +1V$ $V_{out}(t = \infty) = -1.5V$
- B. $V_{out}(t = 0+) = -1V$ $V_{out}(t = \infty) = +1.5V$
- C. $V_{out}(t = 0+) = -1V$ $V_{out}(t = \infty) = -1.5V$**
- D. $V_{out}(t = 0+) = +1V$ $V_{out}(t = \infty) = +1.5V$
- E. None



- =====
- The delay of a static CMOS inverter is minimized if $(W/L)_p / (W/L)_n = \mu_n / \mu_p$.

7. The delay of a static CMOS inverter is minimized if $(W/L)_p / (W/L)_n = \mu_n / \mu_p$.
- A. True
 - B. False
 - C. None
- =====

- The load capacitance of a static CMOS gate has no effect on its VTC

8. The load capacitance of a static CMOS gate has no effect on its VTC
- A. False
 - B. True
 - C. None
- =====

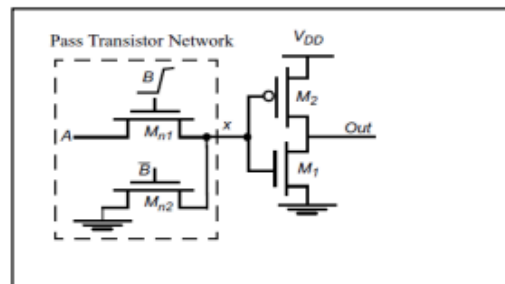
- CMOS Transmission (Pass) Gates , capable of passing both '1' and '0'

10. CMOS Transmission (Pass) Gates , capable of passing both '1' and '0'
- A. Good "1"
 - B. Good "0"
 - C. Poor "1"
 - D. Poor "0"
 - E. Both A and B only
- =====

- What is the logic function performed by this circuit?

11. What is the logic function performed by this circuit?

- A. The circuit is a NOR gate.
- B. The circuit is a XOR gate.
- C. The circuit is a NAND gate.
- D. The circuit is a NOT gate.
- E. None



- =====
- Increasing power supply voltage, VDD, will

12. Increasing power supply voltage, VDD, will

- A. Does not change the speed performance of CMOS gates.
- B. Increase the speed performance of CMOS gates.
- C. Decrease the speed performance of CMOS gates.
- D. None

- =====
- The IN and OUT bus lines in IC design should be in

13. The IN and OUT bus lines in IC design should be in

- A. Metal
- B. Contact
- C. Polysilicon
- D. Diffusion
- E. Silicon
- F. None

- =====
- If an NMOSFET gate's dielectric were changed from SiO₂ to a low-k material with half the permittivity of SiO₂, what would happen to its ID? You may assume that $V_{GS} \geq V_{TN}$

14. If an NMOSFET gate's dielectric were changed from SiO₂ to a low- κ material with half the permittivity of SiO₂, what would happen to its ID? You may assume that $V_{GS} \geq V_{TN}$

- A. Id does not change.
- B. ID being halved.
- C. ID doubled.
- D. Id does not change.
- E. None

- =====
- Which one is the right order for the following the following interconnect fabrication steps : . Etch metal. · Expose photoresist using mask. · Remove all photoresist. · Deposit photoresist. . Deposit metal everywhere.

15. Which one is the right order for the following the following interconnect fabrication steps :

- Etch metal. • Expose photoresist using mask. • Remove all photoresist.
 - Deposit photoresist. • Deposit metal everywhere.
 - A. 1) Deposit metal everywhere. 2) Expose photoresist using mask. 3). Deposit photoresist 4) Etch metal. 5) Remove all photoresist
 - B. 1)) Deposit photoresist 2) Deposit metal everywhere 3) Expose photoresist using mask. 4) Etch metal. 5) Remove all photoresist
 - C. 1) Deposit metal everywhere. 2) Deposit photoresist. 3) Expose photoresist using mask. 4) Etch metal. 5) Remove all photoresist
 - D. 1) Deposit metal everywhere. 2) Expose photoresist using mask. 3) Deposit photoresist. 4) Etch metal. 5) Remove all photoresist
 - E. None
- =====

- =====
- CMOS stands for:

CMOS stands for:

- A. complementary material oxide semiconductor
 - B. complementary metal oxide semiconductor
 - C. complex metal oxide semiconductor
 - D. complex material oxide semiconductor
- =====

- Chip Yield refers :

Chip Yield refers :

- A. Yield drops as chip area increases
 - B. low yield means high cost
 - C. Yield depends on process parameters
 - D. All of the above
- =====

- Which of the following metal layer has Maximum resistance?

Which of the following metal layer has Maximum resistance?

- A. Metal1
 - B. Metal2
 - C. Metal3
 - D. Metal4
- =====

- How do you size NMOS and PMOS transistors to increase the threshold voltage?

How do you size NMOS and PMOS transistors to increase the threshold voltage?

- A. Increase voltage on gate
 - B. Increase voltage on the bias(substrate)
 - C. Lower drain voltage
 - D. Lower drain current
- =====

- =====
- What happens to delay if you increase load capacitance?

What happens to delay if you increase load capacitance?

- A. Increase if driver size stay the same
 - B. Decrease if driver size stay the same
 - C. Has no effect if we make driver smaller
 - D. Delay stay the same
- =====

- What are the limitations in increasing the voltage (power supply) to reduce delay?

What are the limitations in increasing the voltage (power supply) to reduce delay?

- A. Delay limits: Increasing voltage increases delay
 - B. Power limits: Increasing voltage will result in more power
 - C. Area limits: increasing voltage will affect chip area significantly
 - D. A and B
- =====

- What happens if we increase the number of contacts or via from one metal layer to the next?

What happens if we increase the number of contacts or via from one metal layer to the next?

- A. Power dissipation decreased
 - B. Increases resistance and power dissipation
 - C. Overall resistance decrease
 - D. A and C
- =====

- What is the difference between LVS and DRC FOR LAYOUT?

What is the difference between LVS and DRC FOR LAYOUT?

- A. The layout must be drawn according to certain strict design rules DRC
 - B. Both used in layout to verify delay
 - C. None of the above
 - D. LVS compares the netlist extracted from the layout with the schematic to ensure that the layout is an identical match to the cell schematic
 - E. A and D
- =====

- =====
- What are pros/cons of using low V_t , high V_t cells?

What are pros/cons of using low V_t , high V_t cells?

- A. low V_t cell violates design rules DRC
 - B. high V_t cells affect delay of the cell so we should not use in speed path
 - C. high V_t cells affect leakage power
 - D. None of the above
 - E. B and C
- =====

- The main variables/parasitic that affects power dissipations

.The main variables/parasitic that affects power dissipations

- A. low V_t cell violates design rules DRC
 - B. high V_t cells affect delay of the cell so we should not use in speed path
 - C. high V_t cells affect leakage power
 - D. None of the above
 - E. B and C
- =====

- In MOS transistors _____ is used for their gate

7. In MOS transistors, _____ is used for their gate

a) metal b) silicon-di-oxide c) polysilicon d) gallium

In MOS transistors, polycrystalline silicon is used for their gate region instead of metal. Polysilicon gates have replaced all other older devices.

=====

- In N channel MOSFET which is the more negative of the elements?

10. In N channel MOSFET which is the more negative of the elements?

a) source b) gate c) drain

In N channel MOSFET, source is the more negative of the elements and in the case of P channel MOSFET, it is the more positive of the elements.

=====

- MOS transistors consists of what layers ?

6. MOS transistors consists of what layers ?

Metal layer, oxide layer and a semiconductor layer.

=====

- =====
- Silicon-di-oxide is WHAT TYPE OF MATERIALS?

12. Silicon-di-oxide is WHAT TYPE OF MATERIALS?

Oxide Material.

=====

- In CMOS fabrication, nMOS and pMOS are integrated in the same substrate. IS THAT TRUE ?

14. In CMOS fabrication, nMOS and pMOS are integrated in the same substrate. IS THAT TRUE ?

In CMOS fabrication, nMOS and pMOS are integrated in the same chip substrate. n-type and p-type devices are formed in the same structure.

=====

- Which type of CMOS circuits are good and better?

16. Which type of CMOS circuits are good and better?

a) p well b) n well c) all of the mentioned d) none of the mentioned

N-well CMOS circuits are better than p-well CMOS circuits because of lower substrate bias effect.

=====

- Which layer has high capacitance value? metal or diffusion?

25. Which layer has high capacitance value? metal or diffusion?

Diffusion or active layer has high capacitance value due to which it has low or moderate IR drop.

=====

- Which layer has high resistance value? polysilicon or metal ?

26. Which layer has high resistance value? polysilicon or metal ?

Polysilicon layer has high resistance value and due to this it has high IR drop.

=====

- Overall delay increases as n_____ where n is the number of pass transistors connected in series. increases or decreases?

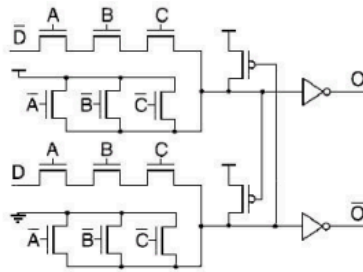
30. Overall delay increases as n_____ where n is the number of pass transistors connected in series. increases or decreases?

**Overall delay increases as n increases where n is the number of pass transistors connected in series.
The overall delay is directly proportional to n^2**

=====

- What is the logic function of the following gate?

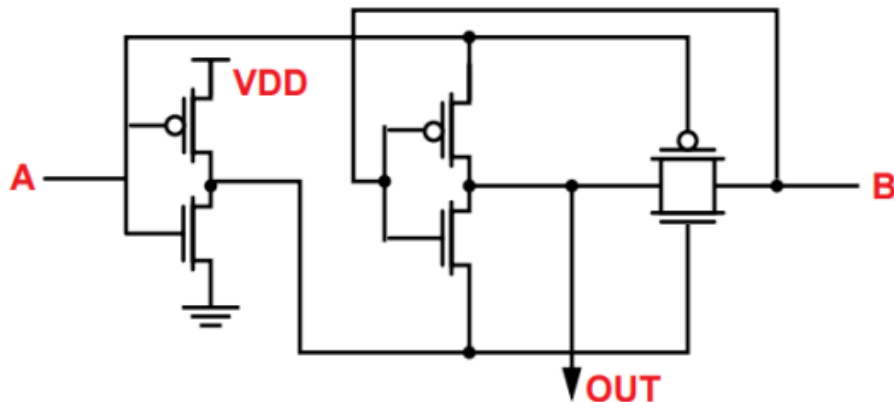
1. What is the logic function of the following gate?



$$O = ABCD$$

- What is the output function of the following circuit?

6. What is the output function of the following circuit?



XOR

True or False

- (T) Transmission gates are needed to pass both 0 and 1
- (T) nMOS pass transistors pull no higher than $V_{DD} - V_{tn}$
- (T) Process can be defined as – a sequence of steps used to form circuits on a wafer
- (T) Field Oxide used for Isolation between devices
- (T) Transistor's current saturates at high V_{ds} values
- (T) Nwell and Substrate must be connected to the power supply within each cell
- (T) If we now want to create an n-type channel below the Si-SiO₂ surface we need to
 - increase V_{GS} . As V_{GS} is increased the Si close to the surface first becomes depleted of holes and only then (at higher V_{GS}) electrons start to build the channel.
- (T) We can define the 'threshold voltage' as the V_{GS} that below it the transistor's current (I_{DS}) effectively drops to zero
- (T) Poly or gate materials have a high-resistance conductor (can be used for short routing)
- (T) We have Design Rules because the fabrication process has minimum/maximum feature sizes that can be produced for each layer
- (F) To set the switching threshold (midpoint) voltage, V_m , to $V_{DD}/2$ in a CMOS inverter, the nMOS transistor must be wider than the pMOS.
- (T) Increasing power supply voltage, V_{DD} , will increase the speed performance of CMOS gates.
- (F) The best way to improve the speed performance of a CMOS circuit is to decrease the channel
- (T) CMOS = Complementary MOS use of both nMOS and pMOS to form a circuit with lowest power consumption.
- (T) Electric Fields: vertical field through gate oxide determines charge induced in channel while horizontal field across channel determines source-to-drain current flow
- (F) pMOS switching behavior device will be on = closed, when $V_{in} > V_{DD} - |V_{tp}|$ and will be off = open, when $V_{in} < V_{DD} - |V_{tp}|$
- (T) 'source' is at lowest potential for nMOS and highest potential for pMOS
- (F) Logic gates are created by using sets of controlled switches. nMOS acts like an assert-low switch and pMOS acts like an assert-high switch
- (T) CMOS is inherently Inverting logic,
- (T) CMOS Transmission Gates , capable of passing both '1' and '0'
- (T) Speed power product is measured as the product of switching delay and gate power dissipation is that true?
- (T) Lithography is Process used to transfer a pattern to a layer on the chip , IS THAT TRUE
- (F) CMOS inverter has 2 regions of operation ,is that true?
- (F) Polysilicon is suitable for connecting to V_{DD} or v_{ss} grid , is that true ?

- (T) During the floor planning step the overall cell is defined, including: cell size, supply network, etc
- (T) If a designer wants a perfectly balanced rise time and fall time for a CMOS inverter driving a capacitive load, Since the mobility of electrons is normally twice the mobility of holes, we need to make the width of PMOS twice as large as the width of NMOS.
- (T) Does the IC have a good chance of implementing the desired logic functions

- Select the correct statement regarding pipeline concept in sequential circuit

Question 7

Complete

Mark 1.00 out of 1.00

Select the correct statement regarding pipeline concept in sequential circuit

- ☐ A. using a pipeline, we can make our fastest path shorter and therefore increase the delay between actions.
- ☐ B. NA
- ☒ C. using a pipeline, we can make our slowest path shorter and therefore reduce the delay between actions.
- ☒ D. some stages may be faster than others, so we need to hold the input to each stage constant until the previous stage is done. We achieve this by adding a register in between the stages

The correct answers are: some stages may be faster than others, so we need to hold the input to each stage constant until the previous stage is done. We achieve this by adding a register in between the stages, using a pipeline, we can make our slowest path shorter and therefore reduce the delay between actions.

- Large (1)----- means small (2)----- , but large (3)-----

Large (1)----- means small (2)----- , but large (3)-----

- ☒ A. (1) W 2(R) 3(C)
- ☐ B. (1) C 2(R) 3(W)
- ☐ C. (1) R 2(W) 3(C)
- ☐ D. (1) C 2(R) 3(W)

The correct answer is: (1) W 2(R) 3(C)

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Align Quiz to Standard

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1. Define Threshold voltage in CMOS ? SELECT ALL RIGHT ANSWER

- A** The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the drain of the MOS transistor below which the gate to source current, I_{GS} effectively drops to zero
- B** The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the bulk of the MOS transistor below which the drain to source current, I_{DS} effectively reach maximum value
- C** The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the source of the MOS transistor below which the drain to source current, I_{DS} effectively drops to zero
- D** All are true



2. a MOS transistor can be considered as ----- (select all that apply)

- A** resistive load in linear region



- B** current source in saturation region
- C** short circuit in cutt off
- D** open circuit all the time



3. If a large ----- is applied this voltage with deplete the Inversion layer .This Voltage effectively pinches off the channel near the source



- A** VGS
- B** VDS
- C** VSB
- D** VGB



4. There are four main different layers in MOS transistors which are

- A** Drain , Source, Gate , bulk
- B** capacitance , resistance, inductance , voltage
- C** waver , package, diod , voltage



5. The transistor **current changes** with the operating temperature but is not affected by mobility

False



6. As the channel length decreases, the depletion region below the gate can no longer be approximated as a rectangular region. So, as L -----



A does not change



B increases



C decreases



7. As V_d is higher, the drain depletion region increases, causing a -- ----- in V_t .



A decrease



B increase



8. For MOS devices, leakage current occurs in what region

A Linear



B Saturation



C cutt off



9. For the same V_{DS} , as V_{GS} increases, The I_{DS} will -----

A increase



B decrease



- C** does not change
- D** has no effect



10. Hot-electron degradation will occur when : When,

- A** a MOS transistor is in Linear region, the electric field across the pinch-off region may be high enough that carriers gain there enough energy to excite electron-hole pairs.
- B** a MOS transistor is in cut-off region, the electric field across the pinch-off region may be high enough that carriers gain there enough energy to excite electron-hole pairs.
- C** a MOS transistor is in saturation, the electric field across the pinch-off region may be high enough that carriers gain there enough energy to excite electron-hole pairs.
- D** In all regions



Add a Question

Multiple Choice

True / False

Short Answer

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1. What are the different operating regions for a MOS transistor?

- ☐ (A) Cutoff region
- ☐ (B) Non-Saturated Region
- ☐ (C) Saturated Region
- ☒ (D) All are correct

2. What are the different MOS layers?

- ☐ (A) n-diffusion
- ☐ (B) p-diffusion
- ☐ (C) Polysilicon
- ☐ (D) Metal
- ☒ (E) all of the above

3. What are the various Silicon wafer Preparation?

- ☐ (A) Crystal growth & doping
- ☐ (B) Ingot trimming & grinding
- ☐ (C) Verilog code preparation
- ☐ (D) Wafer polishing & etching and Wafer cleaning.
- ☒ (E) all of the above are correct except Verilog code preparation

4. If a large V_{ds} is applied this voltage will deplete the Inversion layer. This Voltage effectively pinches off the channel near the source.

- ☐ (T) True
- ☒ (F) False

5. There are only three different layers in MOS transistors which are Drain, Source & Gate

- ☐ (T) True
- ☒ (F) False

6. Threshold voltage in CMOS Defined as : The Threshold voltage, V_T for a MOS transistor can be defined as the voltage applied between the gate and the source of the MOS transistor below which the drain to source current, I_{DS} effectively drops to zero.

☒ True

☐ False

7. The Channel-length modulation, the The current between drain and source terminals is constant and independent of the applied voltage over the terminals. This is not entirely correct. The effective length of the conductive channel is actually modulated by the applied V_{DS} , increasing V_{DS} causes the depletion region at the drain junction to grow, reducing the length of the effective channel.

☒ True

☐ False

8. Define Rise time ? which device nMOS or PMOS determines the Rise time?

In slides rise related to p device size, we measure 20-80% of the rise signal

9. Define Fall time ? which device nMOS or PMOS determines the fall time?

In slides fall related to n device, same we measure 20-80% of fall time

10. Define Delay time ?

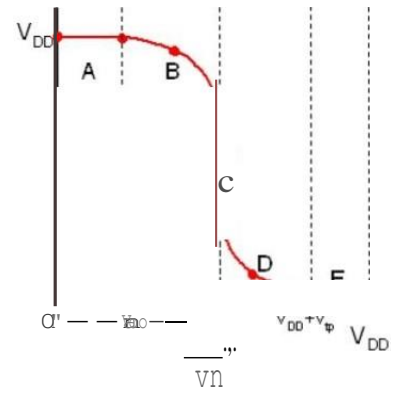
In slides

Between two signal or input and output measured at 50%

11. What are the different operating regions for an NMOS transistor IN EACH REGION AS SHOWN IN THE FIGURE?

In slides

REGION	nMos	pMOS
A		
B		
C		
D		
E		



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1. To have a complement CMOS we do not need

A n-type transistors



B p-type transistors



C package



2. What are the different parts of MOS transistors?

A Drain , Source & Gate and bulk



B Source & Gate



C Drain , Source



D Drain , Source & Gate



E bulk, Drain , Source

3. we can classify IC according to

- A** Signal Type
- B** Signal Name
- C** Analog or digital



4. The first transistor was created in

- A** Bell Labs
- B** China
- C** circuit design



5. Moore's law stated that the number of transistors in ICs doubles every ----- months

- A** 2 years
- B** 17 months
- C** 16 months
- D** 18 months



6. Technology shrinks or scaling, refers to which parameter of the transistor

- A** Drain
- B** source



C Gate length



D bulk



7. We need a ----- to run spice simulations

A device model



B power



C ground



D netlist



E all mentioned

8. in chip design, Wafer made of

A silicon



B Germanium



C copper



D None of mentioned



9. Die is larger than a waver

False



10. package is technology used to interface between die and outside word

True



11. CMOS stands for -----

- A** complementary material oxide state
- B** commuter material or silicon
- C** commuter metal organization states
- D** complementary metal oxide silicon
- E** Non of above



12. which sentences is true a bout Ntype and Ptype transistor

- A** they both made of silicon
- B** they both use as switch
- C** Ntype is slow
- D** ptype is faster than ntype
- E** Both use to build CMOS logic



Add a Question

Multiple Choice

True / False

Short Answer

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1. What is the transistors CMOS technology provides?

- A n-type transistors only
- B p-type transistors only
- C n-type transistors and p-type transistors
- D non of the above



2. What are the different layers in MOS transistors?

- A Drain
- B Source & Gate
- C Drain , Source
- D Drain , Source & Gate
- E bulk, Drain , Source
- F Drain , Source & Gate and bulk



3. IC Classified according to

A Signal Type



B Signal Name



C Number of devices used



4. 1948 , The first ----- was created in Bell Labs

A computer



B transistor



C high performance computer



5. Moore's law was discovered, according to which the number of transistors in ICs doubles every ----- months

A 3 years



B 24 months



C 18 months



D 6 months



6. Technology shrinks or scaling , refers to which parameter of the transistor

A Drain



10. package is technology used to interface between die and outside word

True



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Add a Question